


<b>Search Notes</b>  	<b>Application/Control No.</b>  10597721	<b>Applicant(s)/Patent Under Reexamination</b>  CHEN, JIERU
	<b>Examiner</b>  Kristen C Hayes	<b>Art Unit</b>  3643

SEARCHED			
Class	Subclass	Date	Examiner
119	453, 454, 482, 496,	07/15/2008	KCH
D30	109	"	"
280	62 (txt)	07/16/2008	KCH

SEARCH NOTES		
Search Notes	Date	Examiner
search from primaries Valenti (119), Boehler (280), Vanaman (280)	07/15/2008	KCH
inventor name search	07/16/2008	KCH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner